

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
50001/83:2 USA

APPLICATION NO.

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)APPLICANTS
Brian W. Baird, et al.

FILING DATE

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SS	AA	6 3 0 3 4 0 9	10/16/01	Karpman et al.	438	114	
	AB	5 8 6 4 4 3 0	01/26/99	Dickey et al.	359	559	
	AC	5 8 4 1 0 9 9	11/24/98	Owen et al.	219	121.69	
	AD	5 7 5 1 5 8 5	05/12/98	Cutler et al.	364	474.03	
	AE	5 5 9 3 6 0 6	01/14/97	Owen et al.	219	121.71	
	AF	5 5 4 3 3 6 5	08/06/96	Wills et al.	437	226	
	AG	4 6 1 8 3 8 0	10/21/86	Alcorn et al.	148	187	
	AH	4 5 8 9 1 9 0	05/20/86	Anthony	29	571	
	AI	5 8 7 0 4 2 1	02/09/99	Dahm	372	75	
SS	AJ	4 5 4 1 0 3 5	09/10/85	Carlson et al.	361	414	
	AK						
	AL						

31050 U.S. PTO
10/017497
12/14/01

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SS	AM	WO 01/52004 A1	19 July 2001	PCT	G05B	19/39		
SS	AN	WO 00/73013 A1	07 December 2000	PCT	B23K	26/06		
	AO							
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

SS	AR	Anthony, T.R., "Diodes Formed by Laser Drilling and Diffusion," J. Appl. Phys., Vol. 53 (Dec. 1982), pp. 9154-9164.
SS	AS	Lee, Rex A., et al., "Excimer vs ND:YAG Laser Creation of Silicon Vias for 3D Interconnects," IEEE/CHMT International Electronics Manufacturing Symposium (1992), pp. 358-360.
	AT	
	AU	

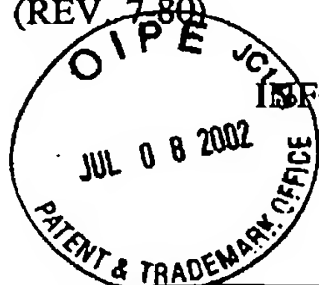
EXAMINER

Stefan S. S. S.

DATE CONSIDERED

9/25/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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50001/83:2 USAAPPLICATION NO.
18,017,497APPLICANTS
Baird et al.FILING DATE
December 14, 2001GROUP
1732INFORMATION DISCLOSURE CITATION
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SS	BA	2001/0034564 A1	10/25/2001	Jones	700	166	04/25/2001
	BB	2002/0033558 A1	03/21/2002	Fahey et al.	264	400	03/09/2001
	BC	6,356,337 B1	03/12/2002	Zemel	355	26	03/08/2000
	BD	6,288,873 B1	09/11/2001	Lundquist et al.	360	234.6	10/18/1999
	BE	6,255,621 B1	07/03/2001	Lundquist et al.	219	121.72	01/31/2000
	BF	6,063,695	05/16/2000	Lin et al.	438	462	
	BG	6,057,180	05/02/2000	Sun et al.	438	132	
	BH	6,037,565	03/14/2000	Hackel et al.	219	121.73	
	BI	6,032,997	03/07/2000	Elliott et al.	294	64.1	
SS	BJ	6,027,660	02/22/2000	Hsiao et al.	216	22	
SS	BK	6,001,268	12/14/1999	Nguyen et al.	216	67	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SS	BL	WO 02/24396 A1	03/28/2002	PCT	B23K	26/36	English	
SS	BM	WO 97/35811	03/14/1997	PCT	C03B	23/00	English	
	BN							
	BO							
	BP							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	BR	
	BS	
	BT	

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Stefan Stancu

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SS	BA	5,963,364	10/05/1999	Leong et al.	359	352	
	BB	5,872,684	02/16/1999	Hadfield et al.	360	103	
	BC	5,779,753	07/14/1998	Vetter et al.	65	105	
	BD	5,739,048	04/14/1998	Kerth et al.	437	226	
SS	BE	4,534,804	08/13/1985	Cade	148	1.5	
	BF						
	BG						
	BH						
	BI						
	BJ						
	BK						

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SS	CA	6,423,925 B1	07/23/2002	Sukhman et al.	219	121.6	02/17/2000
	CB	6,420,245 B1	07/16/2002	Manor	438	460	04/30/2001
	CC	6,069,769	05/30/2000	Dorius et al.	360	103	
	CD	6,060,684	05/09/2000	Moriike	219	121.72	
	CE	5,987,725	11/23/1999	Church et al.	29	407.05	
	CF	5,589,090	12/31/1996	Song	219	121.62	
	CG	5,166,493	11/24/1992	Inagawa et al.	219	121.71	
	CH	4,835,361	05/30/1989	Strom	219	121.85	
SS	CI	4,169,976	10/02/1979	Cirri	219	121 LM	
	CJ						
	CK						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	CL							
	CM							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

SS	CN	"Creation of an Air Bearing Surface by Excimer Laser Patterning of Ceramic," IBM Technical Disclosure Bulletin, September 1991, US, Vol. 34, Issue No. 4B, pp. 59-60; published September 1, 1991, TDB-ACC-NO: NB910959.					
SS	CO	"Method of Preventing Damage to Integrated Circuit Chips during Wafer Dicing," IBM Technical Disclosure Bulletin, May 1992, US, Vol. 34, Issue No. 12, pp. 311-312, published May 1, 1992, TDB-ACC-NO: NN9205311.					
SS	CP	Search Report concerning corresponding International Application No. PCT/US02/00867.					

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SS	DA	6,130,009	10/10/2000	Smith et al.	430	1	_____
SS	DB	5,843,363	12/01/1998	Mitwalsky et al.	264	400	_____
	DC						
	DD						
	DE						
	DF						
	DG						
	DH						
	DI						
	DJ						
	DK						

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	DL							
	DM							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	DN	Written Opinion concerning corresponding International Application No. PCT/US02/00867.					
	DO						
	DP						

EXAMINER

Stefan Saienko

DATE CONSIDERED

9/30/04

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